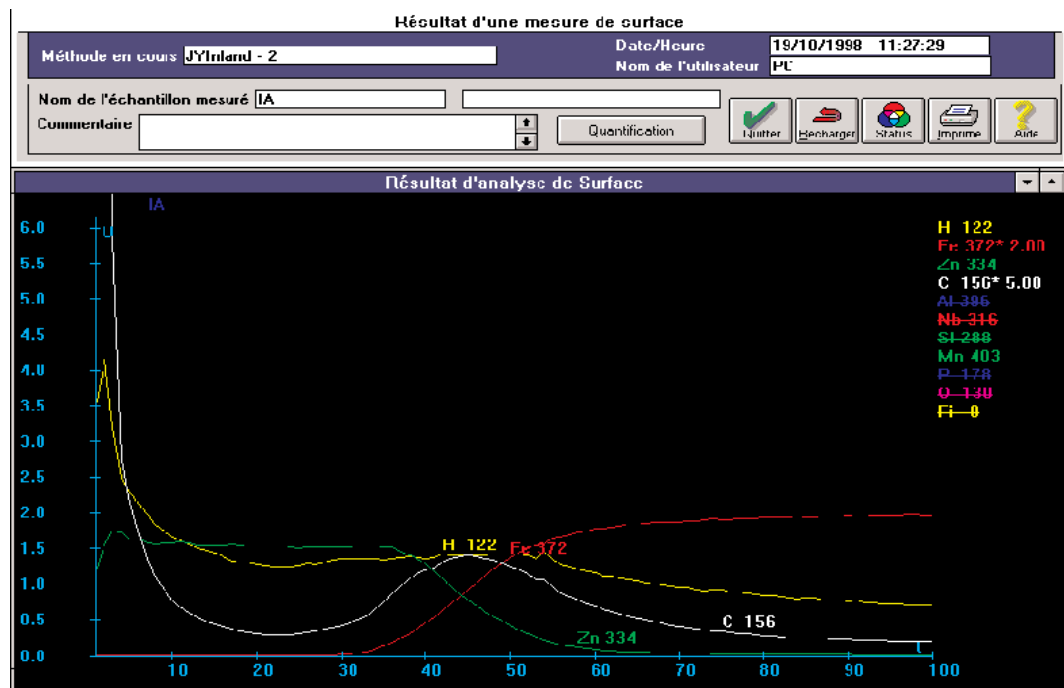


Quick identification of a defect

One of the beauty of GD is speed. The technic is able to do an analysis in minutes, sometimes in seconds. The example shown below was obtained during a demonstration : the problem was to determine the origin of some blisters on a Zn coating.

The patented Centerlite™ permitted to place the defect zone right in front of the anode and the quick analysis reveals a C peak at the interface Zn/Fe indicating that a poor cleaning of the steel before coating was responsible of the blister.



Alternative techniques such as the chemical dissolution of the Zn layer are not able to give the information because the origin of the defect is dissolved with the Zn layer.